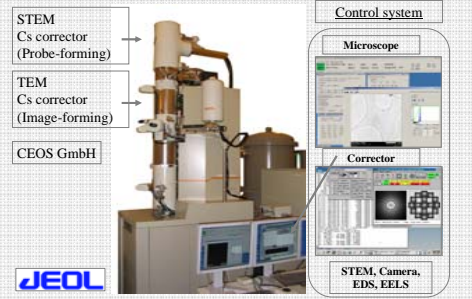


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Cs-corrected TEM:
2200FS / (arrives 2009)



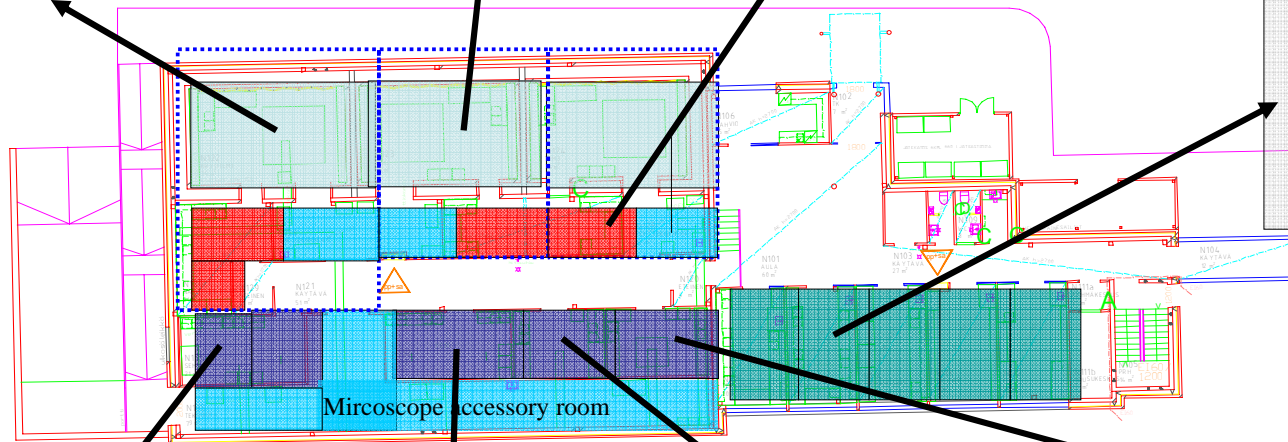
Liquid Helium Cryo-TEM
Jeol 3200FSC (arrives 2009)



- Up to 300kV
- Field-emission gun
- LHe and LN operation
- Lattice resolution 0.204 nm at 18K/RT
- Line resolution 0.14 nm
- Magnification 100-1,200,000X

Silicon Graphics workstations for 3D tomography

Sample Preparation



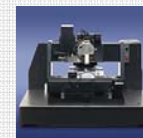
JEOL JSM-7500F
Scanning Electron Microscope
(installation 6/2008)



STM: RHK Variable-temperature STM/AFM



AFM room



1) Veeco
Dimension 5000
SPM



2) Multimode AFM

**Transmission Electron
Microscope (TEM)**



120 kV LaB₆

Two CCD cameras

Sample Holders:

- Multiple specimen holder (4 samples)
- Double tilt
- Single tilt
- Cryo-transfer: multiple (3 samples)
- Cryo transfer: cryo-rotation
- Heating (up to 1300 °C)